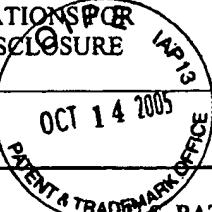


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FORM PTO-1449 (Modified)			ATTY. DOCKET NO. P27064	SERIAL NO. 10/709,362			
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT			APPLICANT: David J. Hathaway, et al				
(Use several sheets if necessary)			FILING DATE: April 29, 2004	GROUP: 2863			
REFERENCE DESIGNATION  U.S. PATENT DOCUMENTS							
EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)							
TL			Aseem Agarwal, et al., "Statistical Timing Analysis for Intra-Die Process Variations with Spatial Correlations," ICCAD '03, November 11-13, 2003, pages 900-907.				
TL			Michael Orshansky, et al., "Impact of Spatial Intrachip Gate Length Variability on the Performance of High-Speed Digital Circuits," IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems, Vol. 21, No.5, May 2002, pages 544-553.				
EXAMINER	<i>Cemylo</i>			DATE CONSIDERED	12/20/05		
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							